

Abstract of the Disclosure

[0066] A method and system employing a plurality of modules having a scan chain combiner coupled to the output of each one of the plurality of modules. The scan chain combiner selects one value per scan chain received from said plurality of modules, wherein the value is indicative of errors in at least one of the plurality of modules. An output mux for communicating the value to a tester via a plurality of chip outputs is coupled to the scan chain combiner.

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